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July 2005

FDS5672 N-Channel PowerTrench[®] MOSFET

FAIRCHILD

SEMICONDUCTOR®

FDS5672

N-Channel PowerTrench[®] MOSFET

60V, 12A, 10m Ω

Features

- $r_{DS(ON)} = 10m\Omega$, $V_{GS} = 10V$, $I_D = 12A$
- $r_{DS(ON)} = 14m\Omega$, $V_{GS} = 6V$, $I_D = 10A$
- High performance trench technology for extremely low ^rDS(ON)
- Low gate charge
- High power and current handling capability

Applications

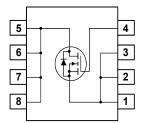
DC/DC converters

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{\mbox{DS}(ON)}$ and fast switching speed.



Branding Dash



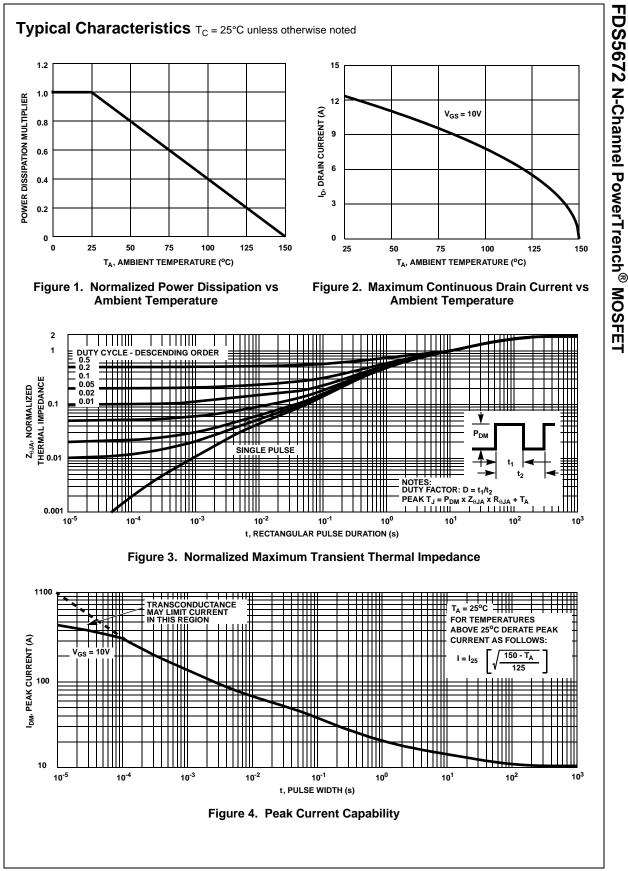
Symbol	Parameter					Ratings		
DSS	Drain to Source Voltage				60			V
GS	Gate to Source Voltage					±20		V
	Drain Cur	rent						
)	Continuou	us (T _C = 25 °C, V _{GS} = 10\	$/, R_{\theta JA} = 50^{\circ}C/W$			12		Α
	Continuou	is (T _C = 25 °C, V _{GS} = 6V,	$R_{\theta JA} = 50^{\circ}C/W$		10			
	Pulsed				Figure 4			Α
AS	Single Pu	lse Avalanche Energy (No	ote 1)		245			mJ
D	Power dis	sipation			2.5			W
D	Derate ab	ove 25°C				20		mW/º
J, T _{STG}	Operating	and Storage Temperatur	e			-55 to 150)	°C
herma	+	cteristics Resistance Junction to Ca	se (Note 2)			25		°C/W
				de (Note 3)		50		°C/W
R _{eja}		Resistance Junction to An Resistance Junction to An		, ,		85		°C/W
	Marki							-
		ng and Ordering	i		<u> </u>		<u> </u>	
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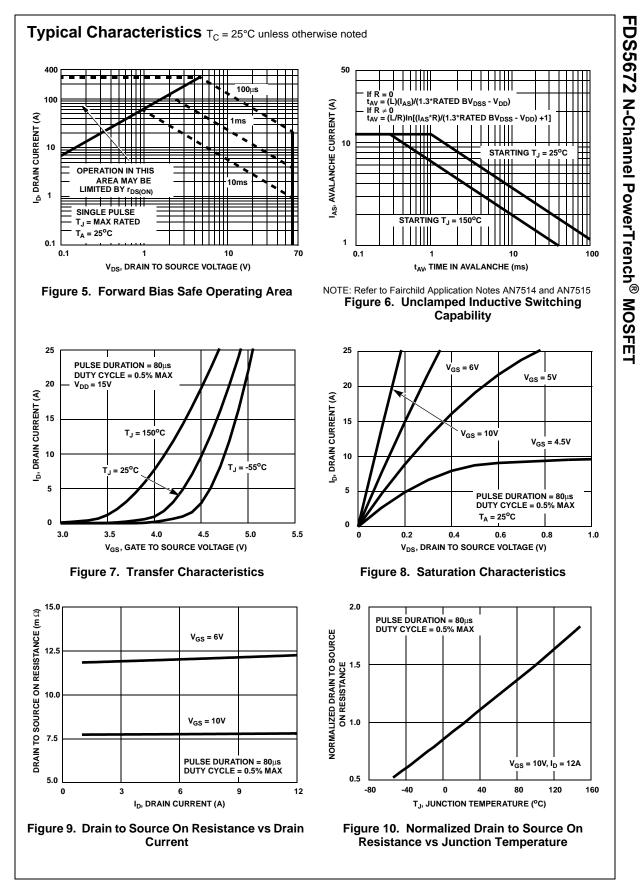
t _{ON}	Turn-On Time		-	-	50	ns
d(ON)	Turn-On Delay Time		-	13	-	ns
r	Rise Time	V _{DD} = 30V, I _D = 12A	-	20	-	ns
d(OFF)	Turn-Off Delay Time	V_{DD} = 30V, I _D = 12A V _{GS} = 10V, R _{GS} = 9.1Ω	-	35	-	ns
f	Fall Time		-	14	-	ns
t _{OFF}	Turn-Off Time		-	-	64	ns

Drain-Source Diode Characteristics

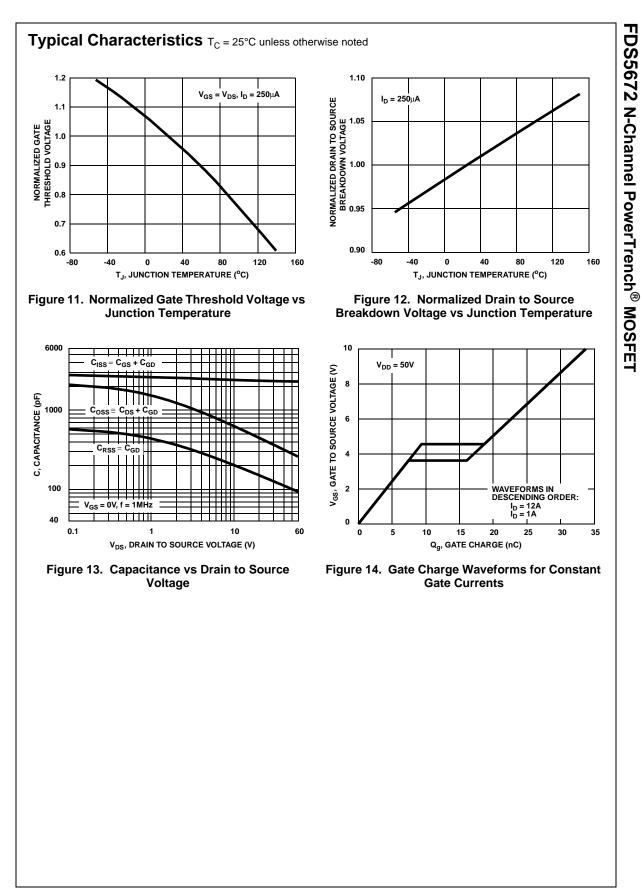
V	Source to Droip Diade Veltage	I _{SD} = 12A	-	-	1.25	V
V _{SD}	Source to Drain Diode Voltage	I _{SD} = 6A	-	-	1.0	V
t _{rr}	Reverse Recovery Time	I _{SD} =12A, dI _{SD} /dt = 100A/μs	-	-	39	ns
Q _{RR}	Reverse Recovered Charge	I _{SD} =12A, dI _{SD} /dt = 100A/μs	-	-	40	nC

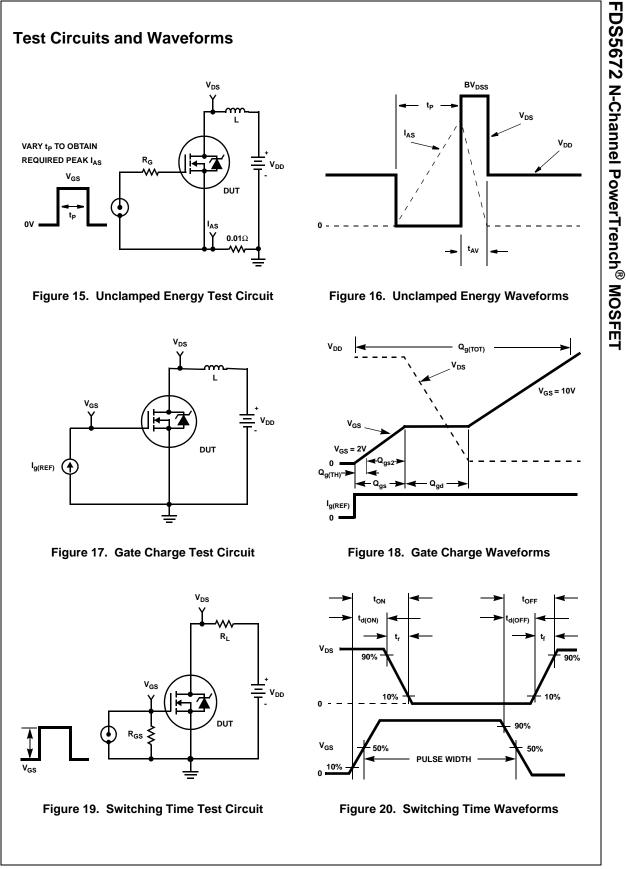
Notes:
1: Starting T_J = 25°C, L = 1mH, I_{AS} = 22A, V_{DD} = 60V, V_{GS} = 10V.
2: R_{θJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{θJC} is guaranteed by design while R_{θJA} is determined by the user's board design.
3: R_{θJA} is measured with 1.0 in² copper on FR-4 board.





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Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the SO8 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta,JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized

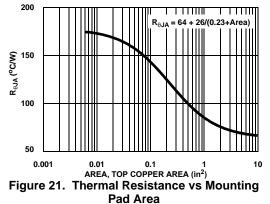
maximum transient thermal impedance curve.

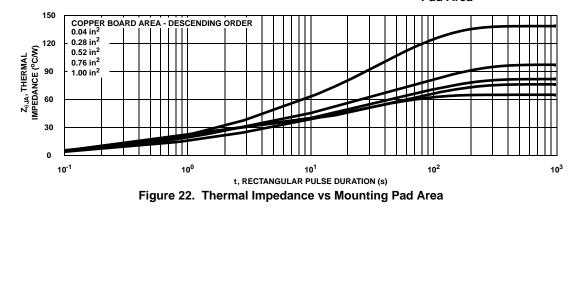
Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2. The area, in square inches is the top copper area including the gate and source pads.

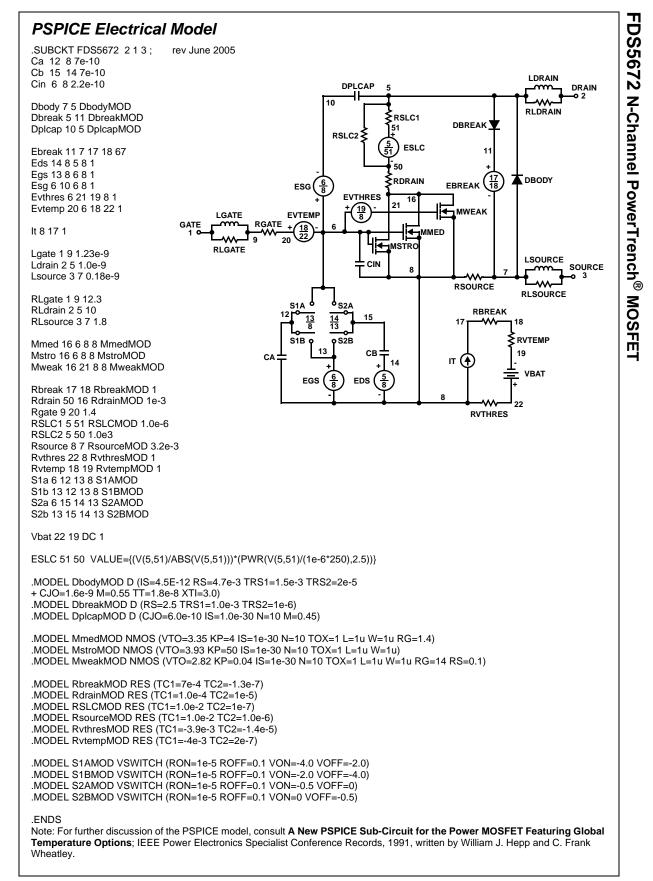
$$R_{\theta JA} = 64 + \frac{26}{0.23 + Area}$$
 (EQ. 2)

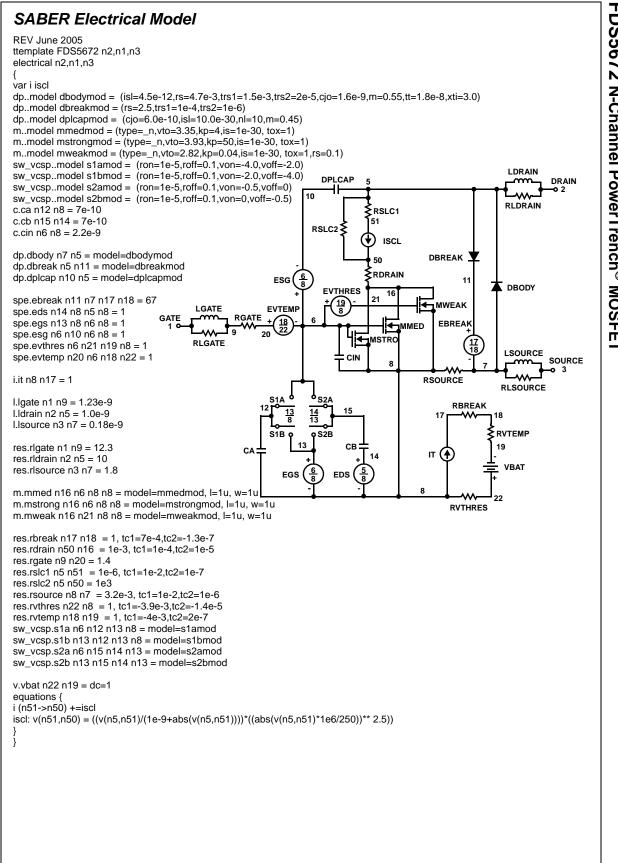
The transient thermal impedance $(Z_{\theta,JA})$ is also effected by varied top copper board area. Figure 22 shows the effect of copper pad area on single pulse transient thermal impedance. Each trace represents a copper pad area in square inches corresponding to the descending list in the graph. Spice and SABER thermal models are provided for each of the listed pad areas.

Copper pad area has no perceivable effect on transient thermal impedance for pulse widths less than 100ms. For pulse widths less than 100ms the transient thermal impedance is determined by the die and package. Therefore, CTHERM1 through CTHERM5 and RTHERM1 through RTHERM5 remain constant for each of the thermal models. A listing of the model component values is available in Table 1.









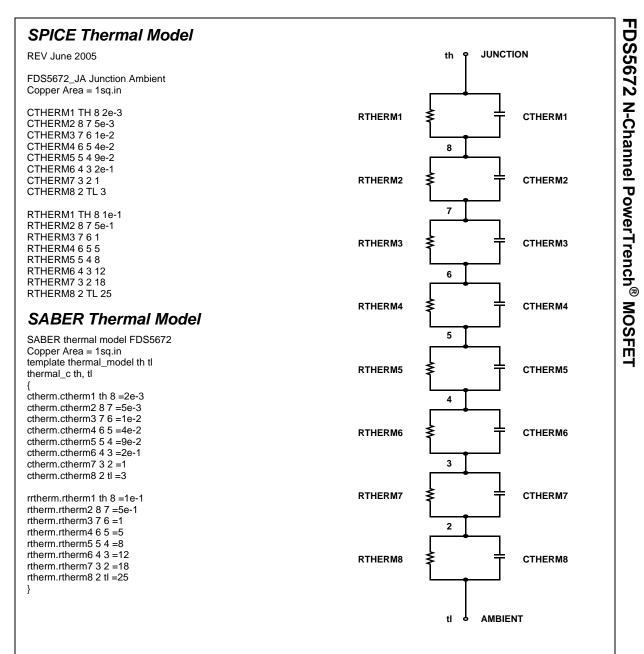


TABLE 1. THERMAL MODELS

COMPONANT	0.04 in ²	0.28 in ²	0.52 in ²	0.76 in ²	1.0 in ²
CTHERM6	1.2e-1	1.5e-1	2.0e-1	2.0e-1	2.0e-1
CTHERM7	0.5	1.0	1.0	1.0	1.0
CTHERM8	1.3	2.8	3.0	3.0	3.0
RTHERM6	26	20	15	13	12
RTHERM7	39	24	21	19	18
RTHERM8	55	38.7	31.3	29.7	25

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